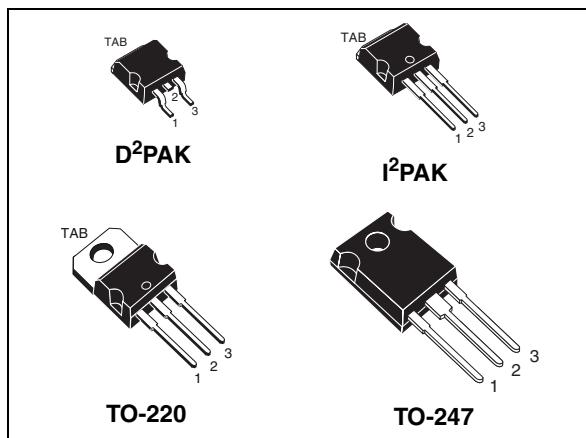


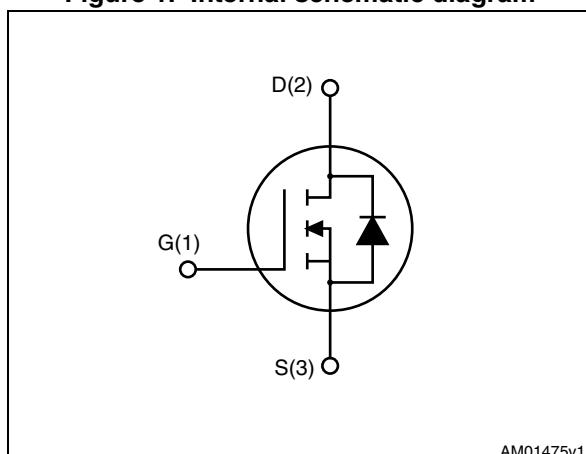
# STB34N65M5, STI34N65M5, STP34N65M5, STW34N65M5

N-channel 650 V, 0.09 Ω typ., 28 A MDmesh™ V Power MOSFETs  
in D<sup>2</sup>PAK, I<sup>2</sup>PAK, TO-220 and TO-247 packages

Datasheet - production data



**Figure 1. Internal schematic diagram**



## Features

Order codes	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STB34N65M5			
STI34N65M5	710 V	0.11 Ω	
STP34N65M5			
STW34N65M5			28 A

- Worldwide best R<sub>DS(on)</sub> \* area
- Higher V<sub>DSS</sub> rating and high dv/dt capability
- Excellent switching performance
- 100% avalanche tested

## Applications

- Switching applications

## Description

These devices are N-channel MDmesh™ V Power MOSFETs based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low on-resistance, which is unmatched among silicon-based Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

**Table 1. Device summary**

Order codes	Marking	Packages	Packaging
STB34N65M5	34N65M5	D <sup>2</sup> PAK	Tape and reel
STI34N65M5		I <sup>2</sup> PAK	
STP34N65M5		TO-220	
STW34N65M5		TO-247	Tube

## Contents

<b>1</b>	<b>Electrical ratings</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics</b>	<b>4</b>
2.1	Electrical characteristics (curves)	6
<b>3</b>	<b>Test circuits</b>	<b>9</b>
<b>4</b>	<b>Package mechanical data</b>	<b>10</b>
<b>5</b>	<b>Packaging mechanical data</b>	<b>19</b>
<b>6</b>	<b>Revision history</b>	<b>21</b>

# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	28	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	17.7	A
$I_{DM}^{(1)}$	Drain current (pulsed)	112	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	190	W
$dv/dt^{(1)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(2)}$	MOSFET dv/dt ruggedness	50	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	$^\circ\text{C}$

1.  $I_{SD} \leq 28$  A,  $di/dt \leq 400$  A/ $\mu\text{s}$ ;  $V_{DS}$  peak <  $V_{(\text{BR})DSS}$ ,  $V_{DD}=400$  V.

2.  $V_{DS} \leq 480$  V

**Table 3. Thermal data**

Symbol	Parameter	Value			Unit
		D <sup>2</sup> PAK	TO-220, I <sup>2</sup> PAK	TO-247	
$R_{thj-case}$	Thermal resistance junction-case max	0.66			$^\circ\text{C/W}$
$R_{thj-pcb}$	Thermal resistance junction-pcb max <sup>(1)</sup>	30			$^\circ\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max		62.5	50	$^\circ\text{C/W}$

1. When mounted on 1 inch<sup>2</sup> FR-4, 2 Oz copper board.

**Table 4. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	7	A
$E_{AS}$	Single pulse avalanche energy (starting $t_j=25^\circ\text{C}$ , $I_d=I_{AR}$ ; $V_{dd}=50$ )	510	mJ

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 5. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0$	650			V
$I_{\text{DSS}}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 650 \text{ V}$ $V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$			1 100	$\mu\text{A}$ $\mu\text{A}$
$I_{\text{GSS}}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 25 \text{ V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3	4	5	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 14 \text{ A}$		0.09	0.11	$\Omega$

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{\text{iss}}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$	-	2700	-	pF
$C_{\text{oss}}$	Output capacitance		-	75	-	pF
$C_{\text{rss}}$	Reverse transfer capacitance		-	6.3	-	pF
$C_{o(\text{tr})}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0 \text{ to } 520 \text{ V}, V_{GS} = 0$	-	220	-	pF
$C_{o(\text{er})}^{(2)}$	Equivalent capacitance energy related		-	63	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz open drain}$	-	1.95	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 14 \text{ A}, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 18</a> )	-	62.5	-	nC
$Q_{gs}$	Gate-source charge		-	17	-	nC
$Q_{gd}$	Gate-drain charge		-	28	-	nC

1. Time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{\text{oss}}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$
2. Energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{\text{oss}}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 7. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_d(v)$	Voltage delay time	$V_{DD} = 400 \text{ V}$ , $I_D = 18 \text{ A}$ , $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 19</a> and <a href="#">Figure 22</a> )	-	59	-	ns
$t_r(v)$	Voltage rise time		-	8.7	-	ns
$t_f(i)$	Current fall time		-	7.5	-	ns
$t_c(\text{off})$	Crossing time		-	12	-	ns

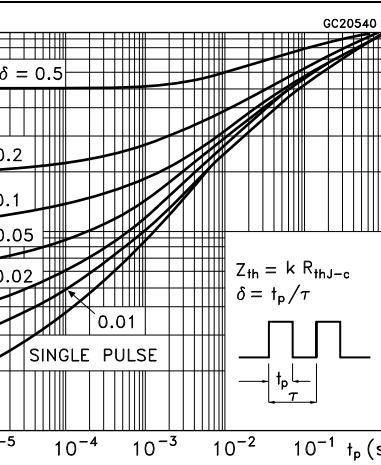
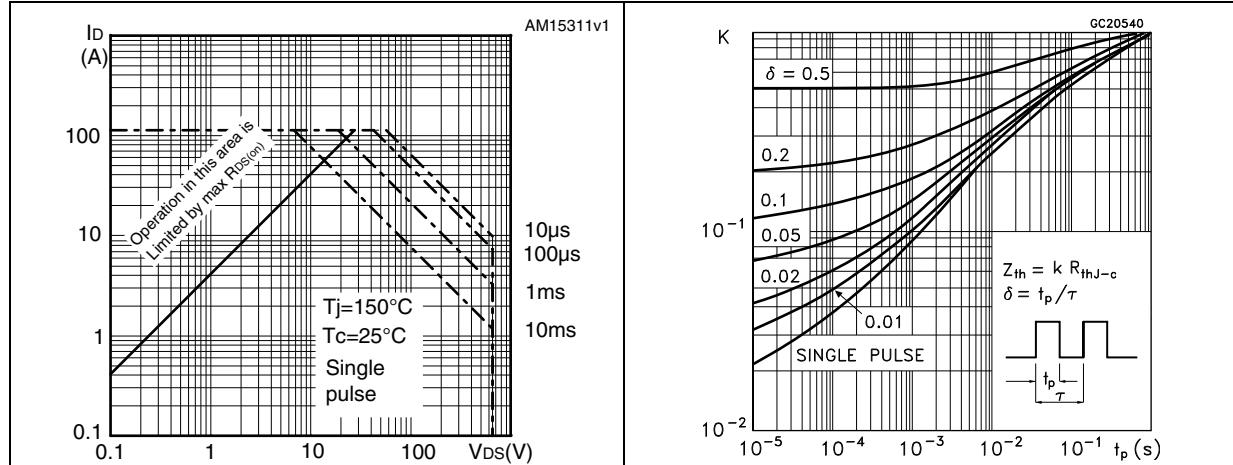
**Table 8. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		28	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		112	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 28 \text{ A}$ , $V_{GS} = 0$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 28 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$ (see <a href="#">Figure 22</a> )	-	350		ns
$Q_{rr}$	Reverse recovery charge		-	5.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	32		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 28 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$ , $T_j = 150^\circ\text{C}$ (see <a href="#">Figure 22</a> )	-	422		ns
$Q_{rr}$	Reverse recovery charge		-	7.4		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	35		A

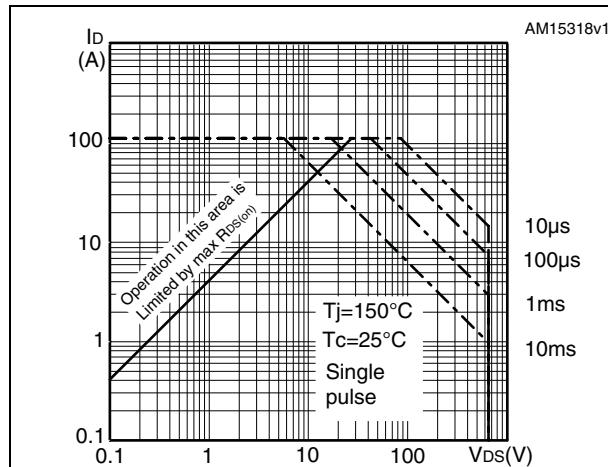
1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

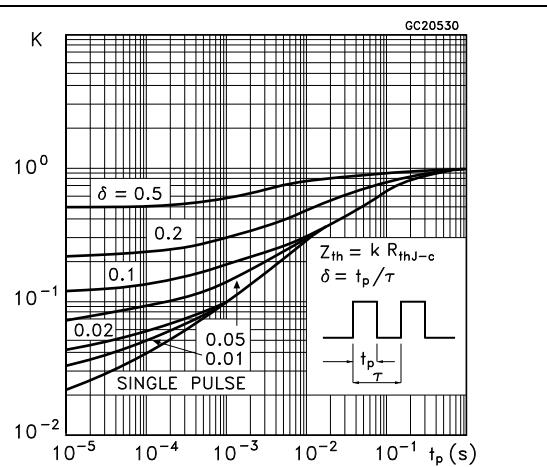
**Figure 2. Safe operating area for D<sup>2</sup>PAK, I<sup>2</sup>PAK and TO-220**



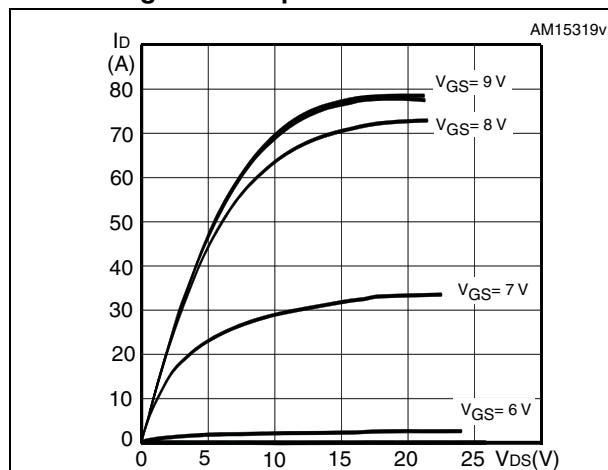
**Figure 4. Safe operating area for TO-247**



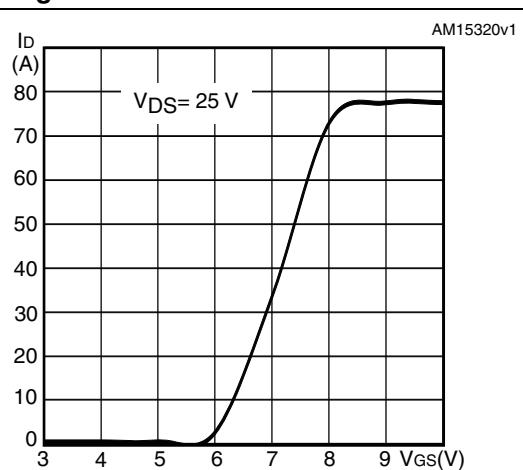
**Figure 5. Thermal impedance for TO-247**

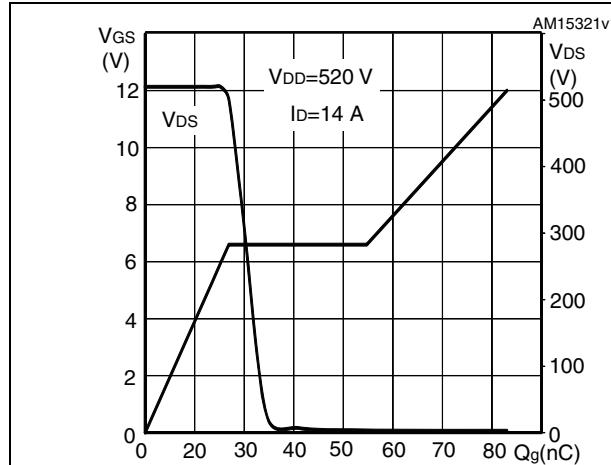
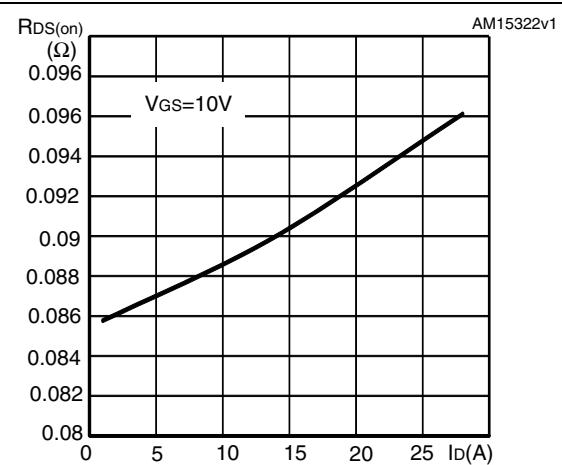
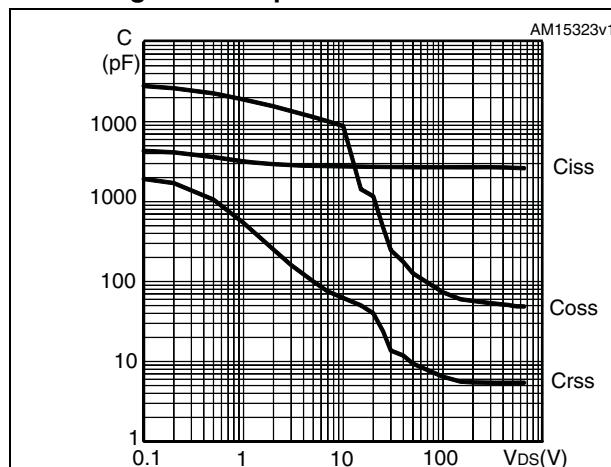
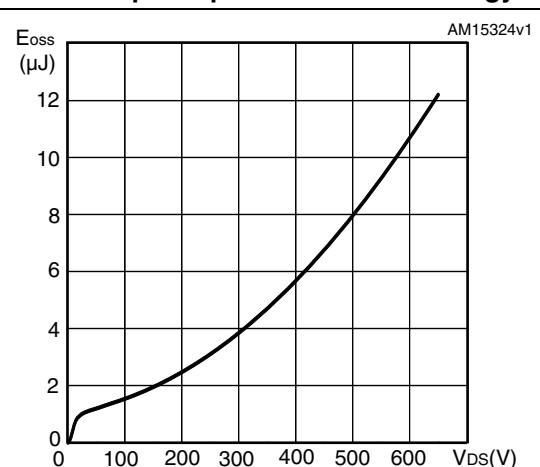
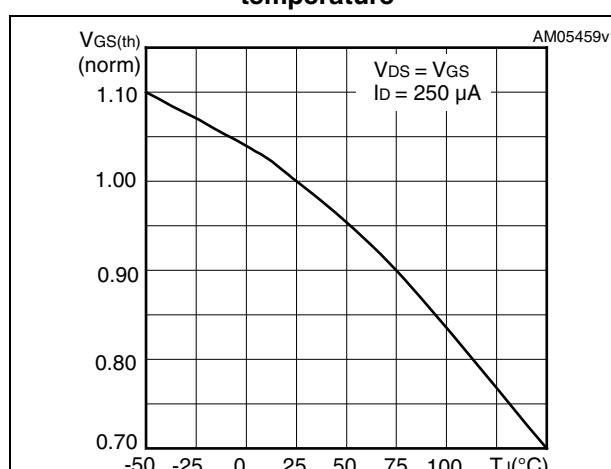
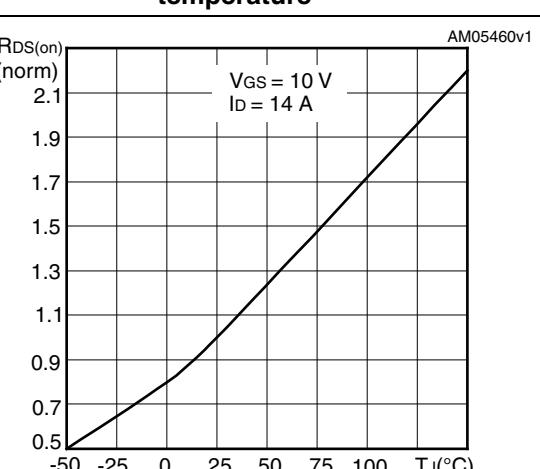


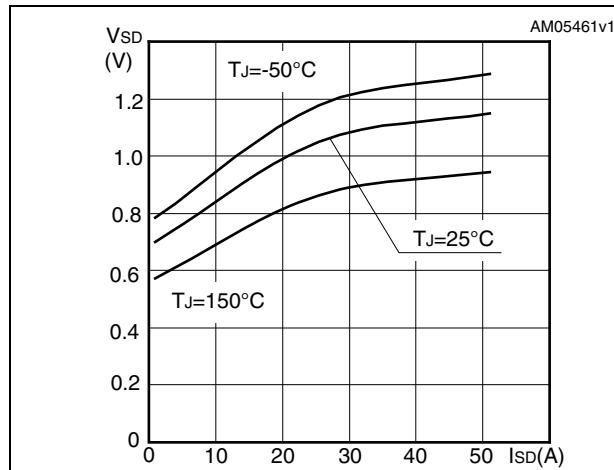
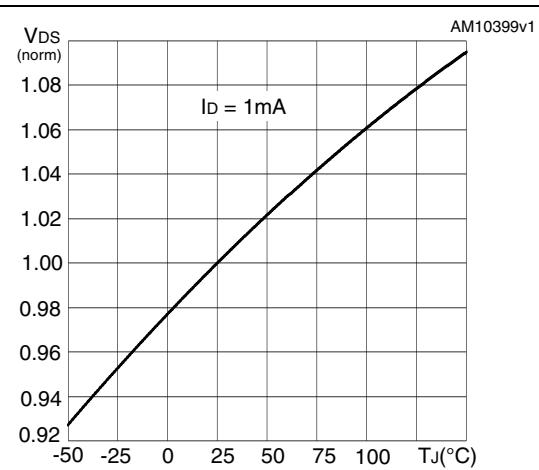
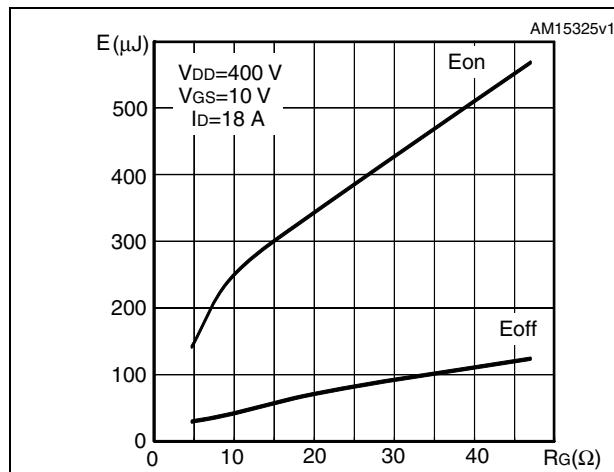
**Figure 6. Output characteristics**



**Figure 7. Transfer characteristics**



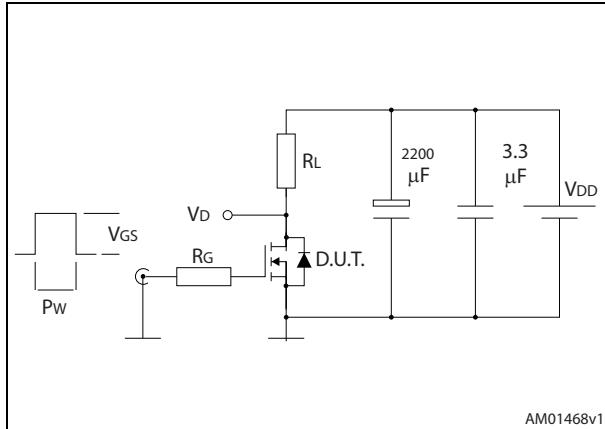
**Figure 8. Gate charge vs gate-source voltage****Figure 9. Static drain-source on-resistance****Figure 10. Capacitance variations****Figure 11. Output capacitance stored energy****Figure 12. Normalized gate threshold voltage vs temperature****Figure 13. Normalized on-resistance vs temperature**

**Figure 14. Source-drain diode forward characteristics****Figure 15. Normalized  $V_{DS}$  vs temperature****Figure 16. Switching losses vs gate resistance (1)**

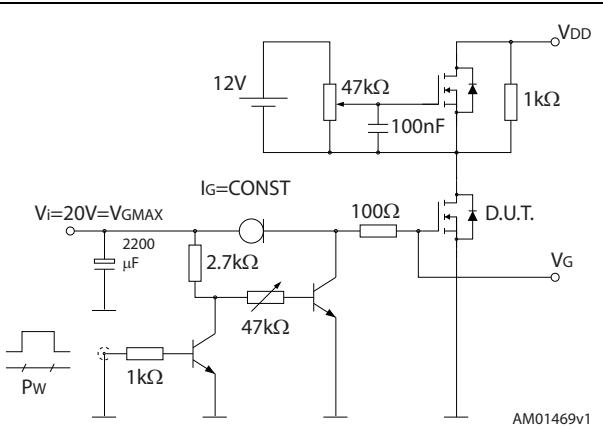
1.  $E_{on}$  including reverse recovery of a SiC diode

### 3 Test circuits

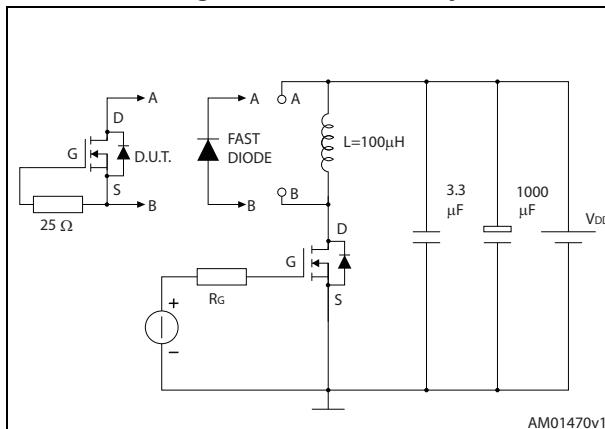
**Figure 17. Switching times test circuit for resistive load**



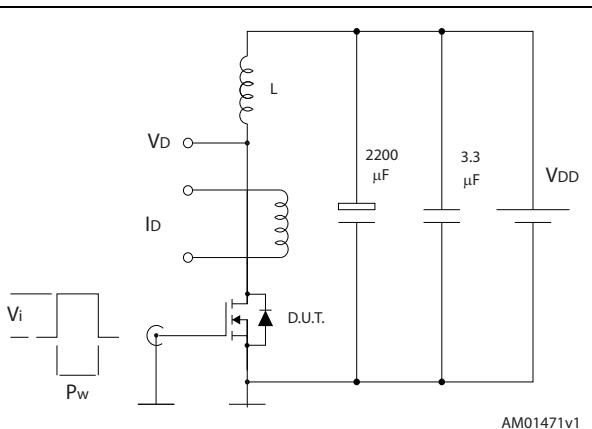
**Figure 18. Gate charge test circuit**



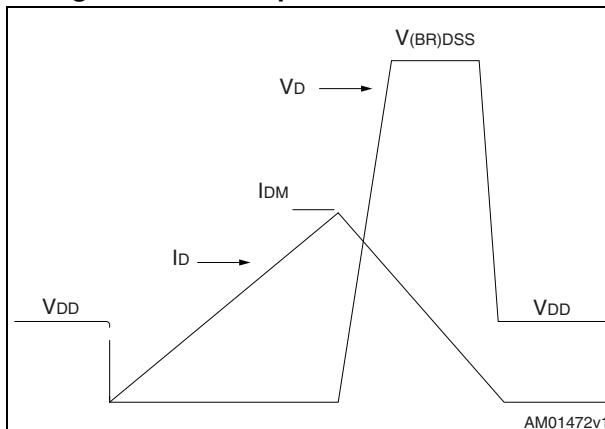
**Figure 19. Test circuit for inductive load switching and diode recovery times**



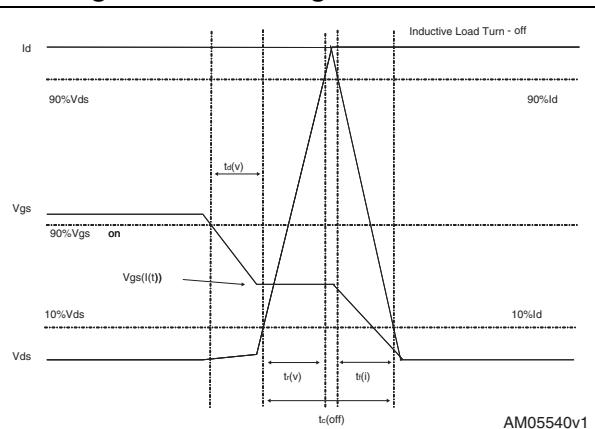
**Figure 20. Unclamped inductive load test circuit**



**Figure 21. Unclamped inductive waveform**



**Figure 22. Switching time waveform**

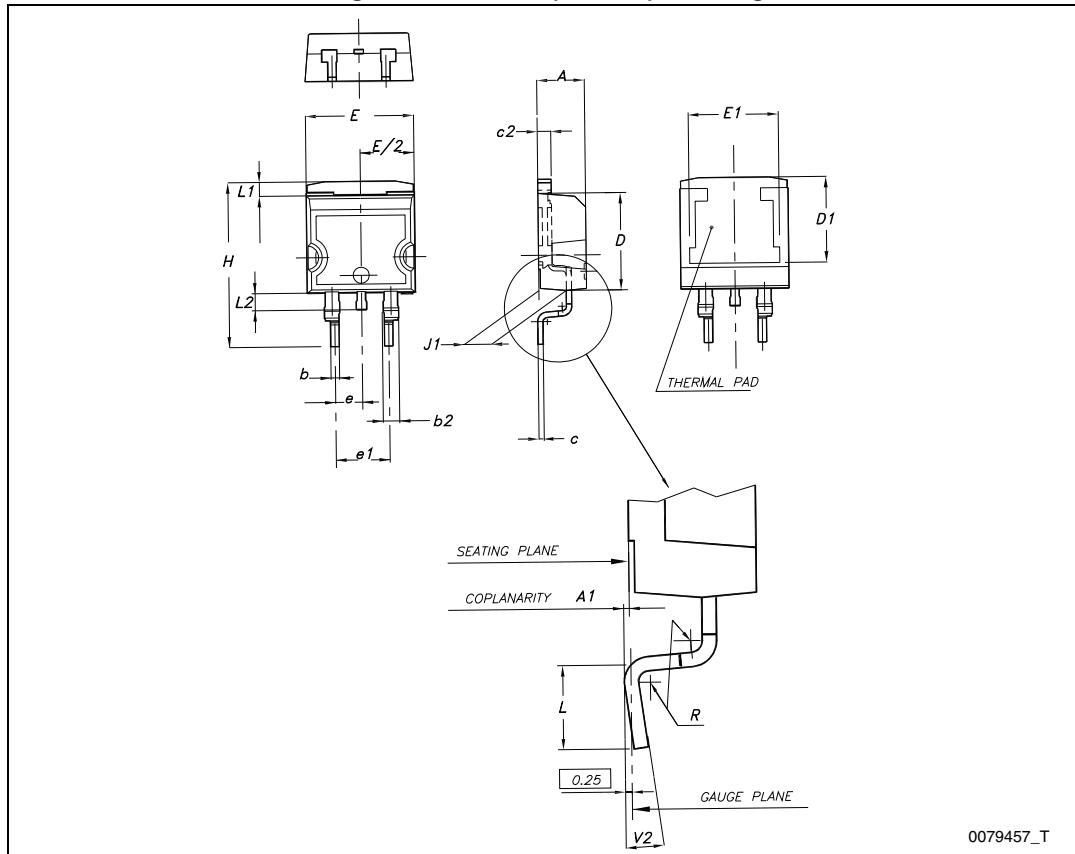
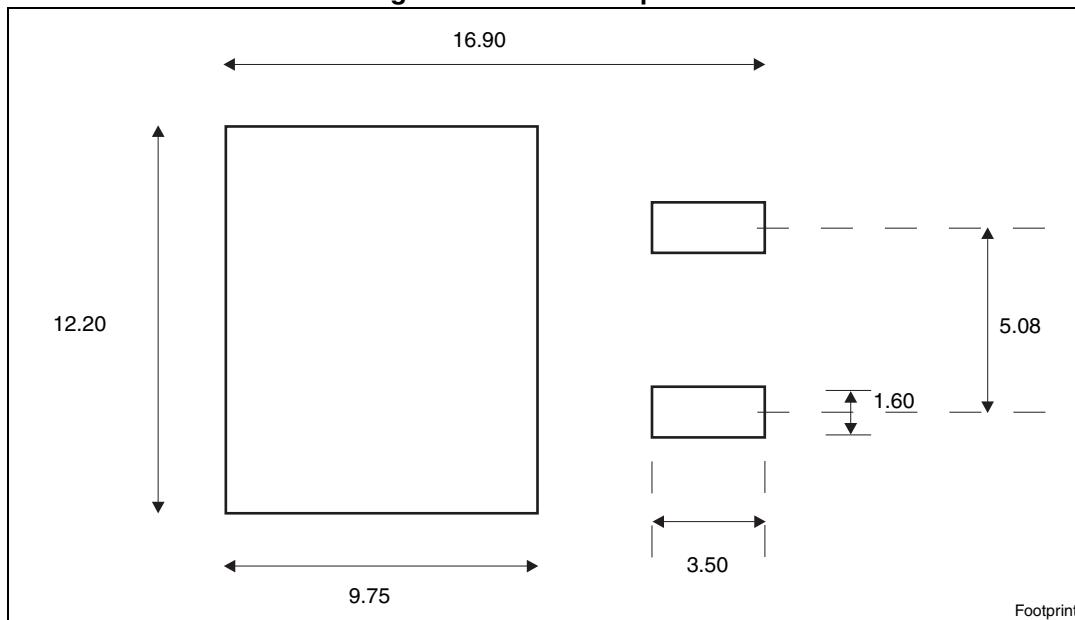


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

**Table 9. D<sup>2</sup>PAK (TO-263) mechanical data**

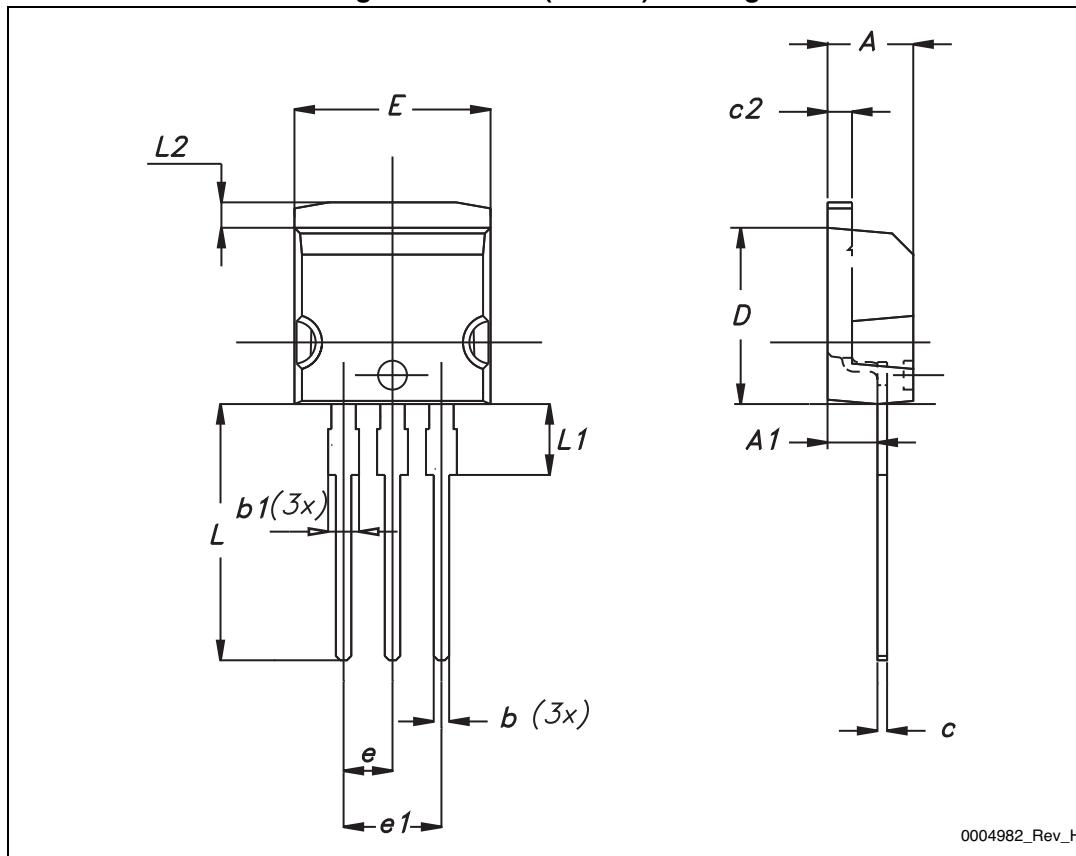
Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50		
E	10		10.40
E1	8.50		
e		2.54	
e1	4.88		5.28
H	15		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.4	
V2	0°		8°

**Figure 23. D<sup>2</sup>PAK (TO-263) drawing****Figure 24. D<sup>2</sup>PAK footprint<sup>(a)</sup>**

a. All dimension are in millimeters

**Table 10. I<sup>2</sup>PAK (TO-262) mechanical data**

DIM.	mm.		
	min.	typ	max.
A	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
c	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
e	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

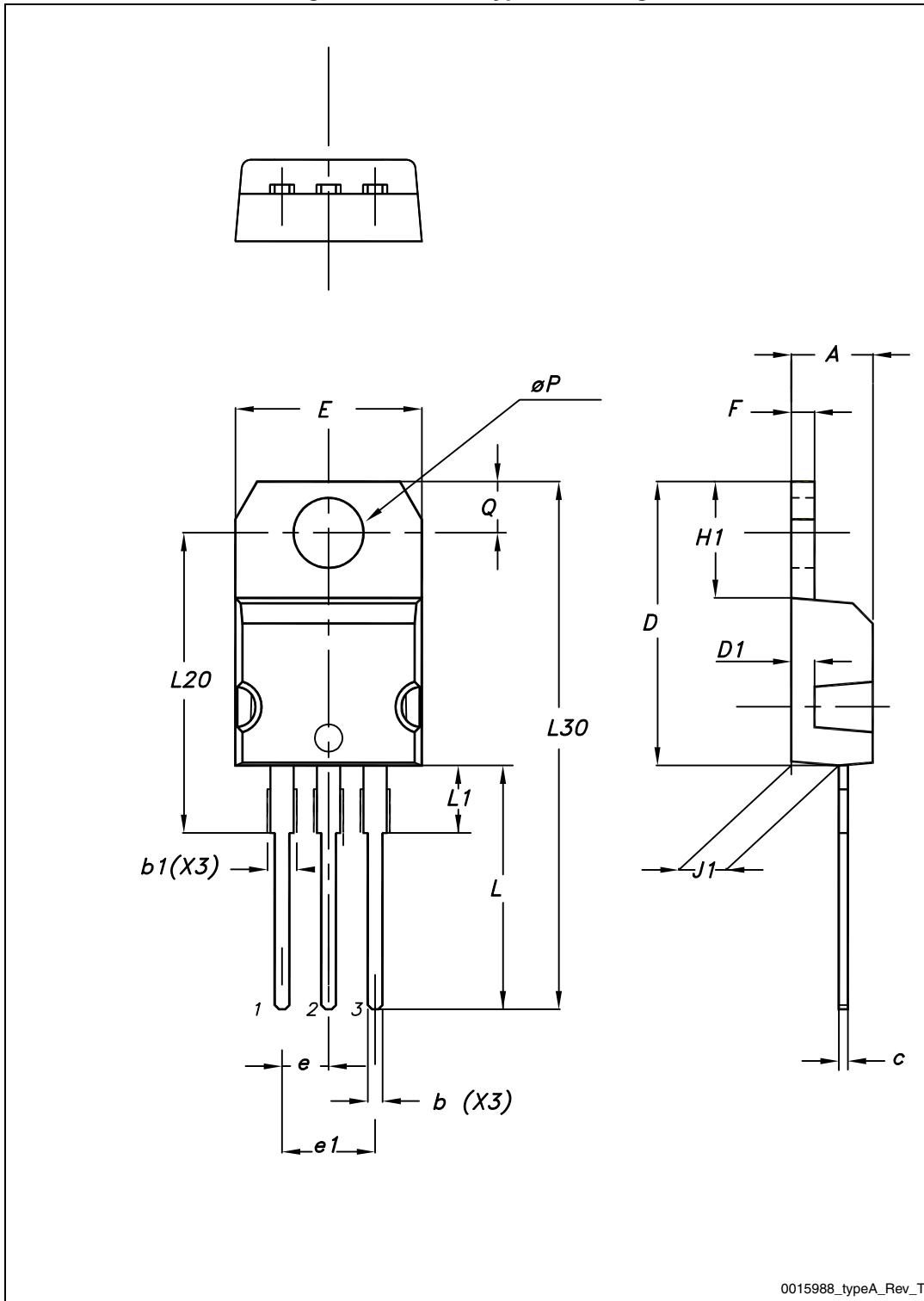
Figure 25. I<sup>2</sup>PAK (TO-262) drawing

0004982\_Rev\_H

**Table 11. TO-220 type A mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95

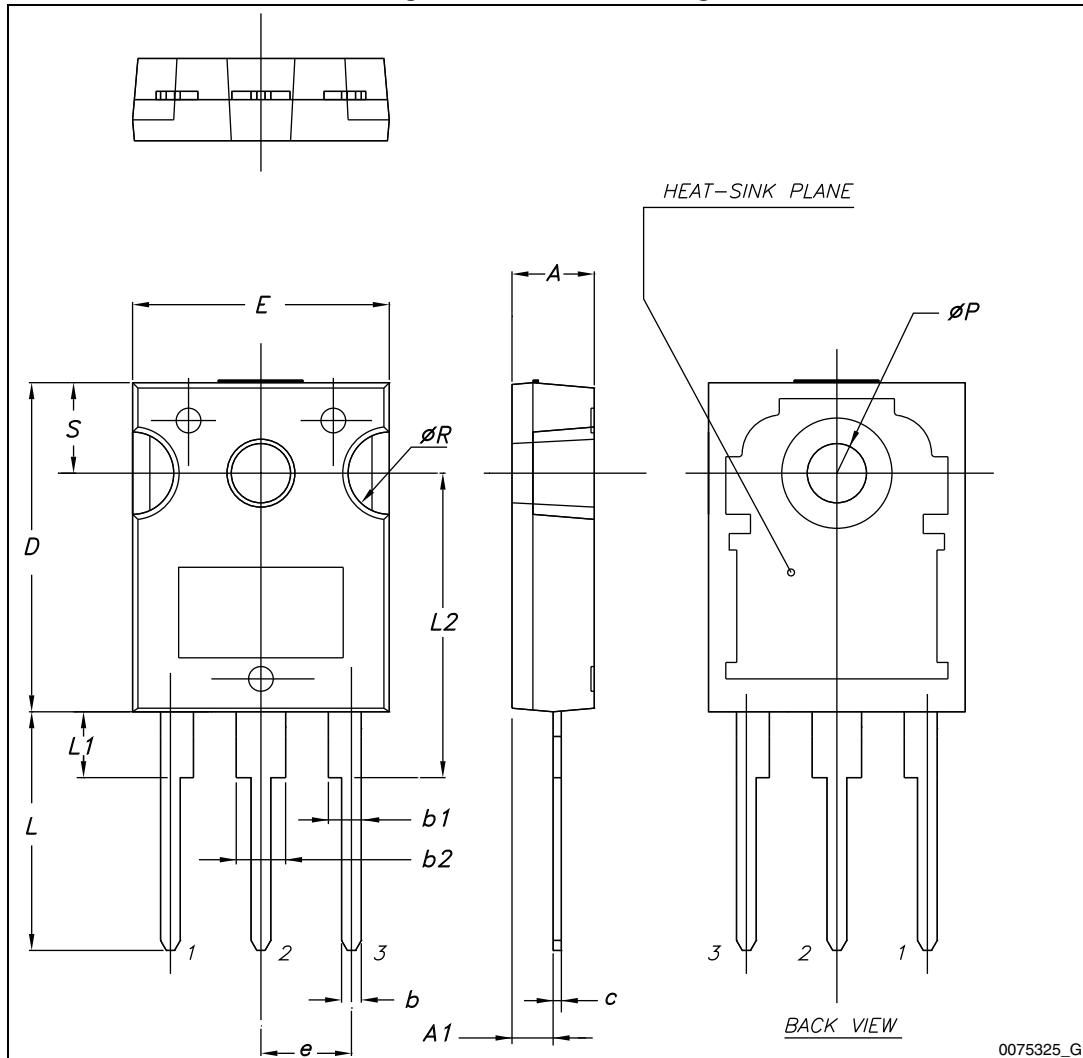
Figure 26. TO-220 type A drawing



**Table 12. TO-247 mechanical data**

Dim.	mm.		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

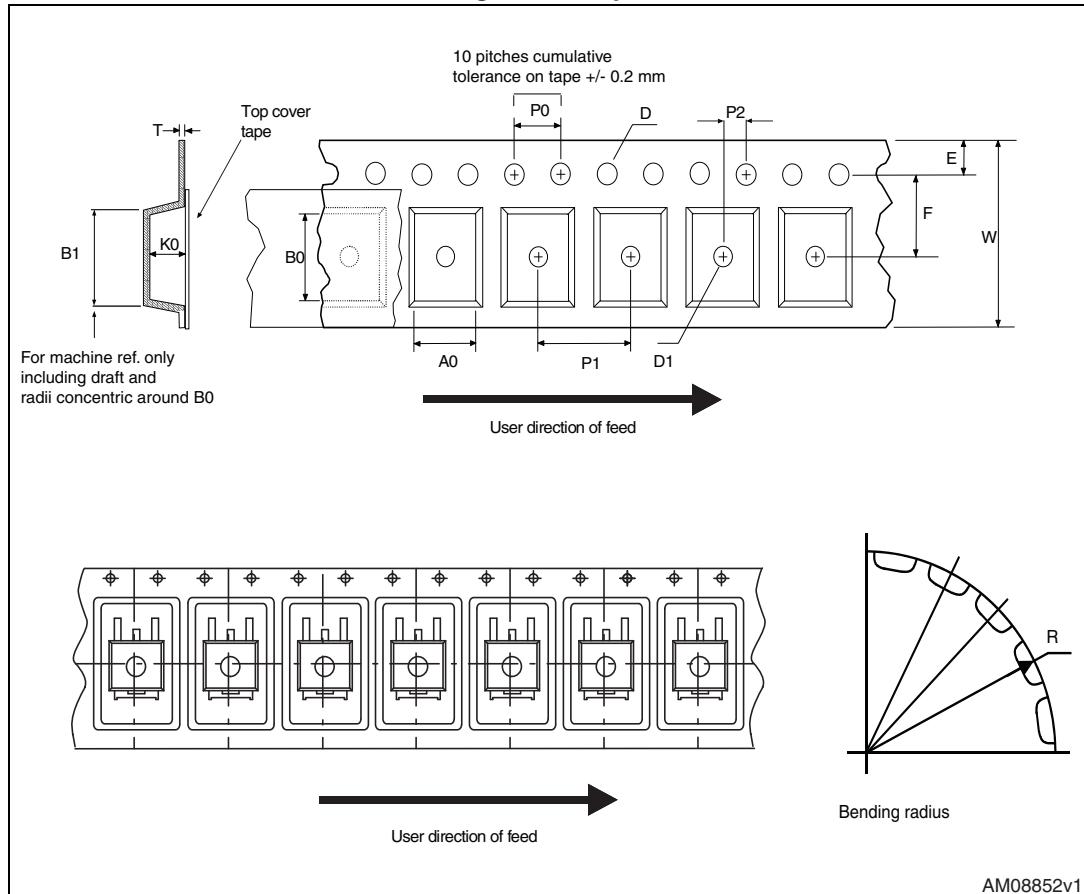
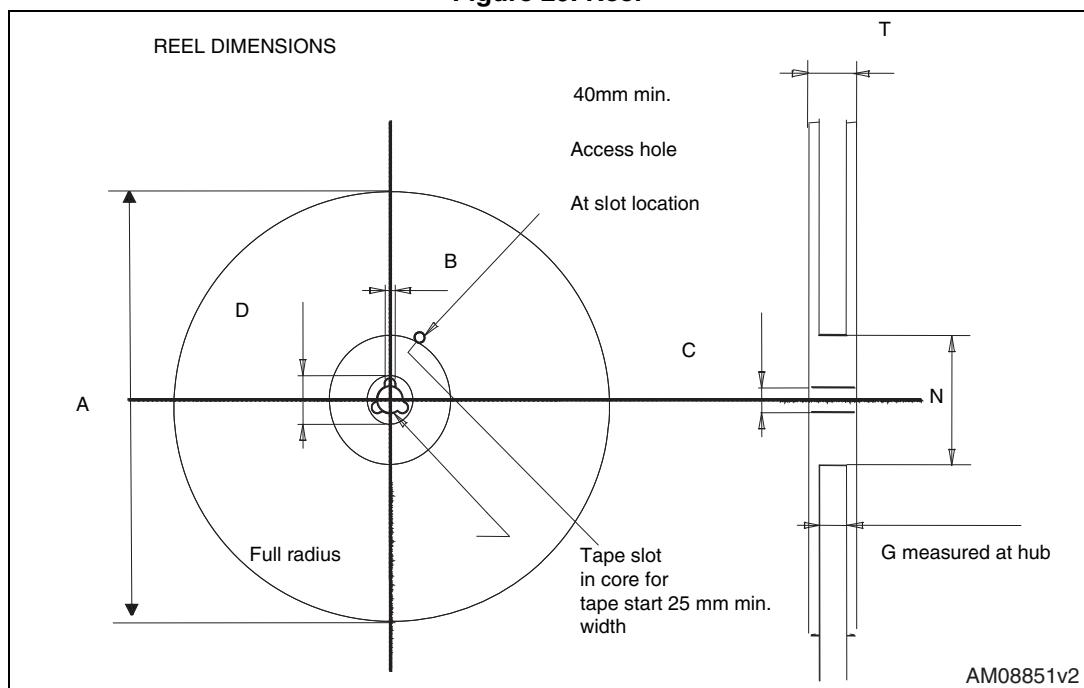
Figure 27. TO-247 drawing



## 5 Packaging mechanical data

**Table 13. D<sup>2</sup>PAK (TO-263) tape and reel mechanical data**

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1		Base qty	1000
P2	1.9	2.1		Bulk qty	1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

**Figure 28. Tape****Figure 29. Reel**

## 6 Revision history

Table 14. Document revision history

Date	Revision	Changes
23-Feb-2012	1	First release.
15-Oct-2012	2	<ul style="list-style-type: none"><li>– Added package, mechanical data: I<sup>2</sup>PAKFP</li><li>– Updated <a href="#">Table 1: Device summary</a>, <a href="#">Table 2: Absolute maximum ratings</a>, <a href="#">Table 3: Thermal data</a>.</li><li>– Minor text changes.</li><li>– Curves inserted</li></ul>
02-Oct-2013	3	<ul style="list-style-type: none"><li>– The part numbers STF34N65M5 and STFI34N65M5 have been moved to the separate datasheet</li><li>– Modified: <a href="#">Figure 1</a></li><li>– Added: MOSFET dv/dt ruggedness parameter in <a href="#">Table 2</a></li><li>– Updated: <a href="#">Section 4: Package mechanical data</a> and <a href="#">Section 5: Packaging mechanical data</a></li><li>– Minor text changes</li></ul>

**Please Read Carefully:**

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

**UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.**

**ST PRODUCTS ARE NOT DESIGNED OR AUTHORIZED FOR USE IN: (A) SAFETY CRITICAL APPLICATIONS SUCH AS LIFE SUPPORTING, ACTIVE IMPLANTED DEVICES OR SYSTEMS WITH PRODUCT FUNCTIONAL SAFETY REQUIREMENTS; (B) AERONAUTIC APPLICATIONS; (C) AUTOMOTIVE APPLICATIONS OR ENVIRONMENTS, AND/OR (D) AEROSPACE APPLICATIONS OR ENVIRONMENTS. WHERE ST PRODUCTS ARE NOT DESIGNED FOR SUCH USE, THE PURCHASER SHALL USE PRODUCTS AT PURCHASER'S SOLE RISK, EVEN IF ST HAS BEEN INFORMED IN WRITING OF SUCH USAGE, UNLESS A PRODUCT IS EXPRESSLY DESIGNATED BY ST AS BEING INTENDED FOR "AUTOMOTIVE, AUTOMOTIVE SAFETY OR MEDICAL" INDUSTRY DOMAINS ACCORDING TO ST PRODUCT DESIGN SPECIFICATIONS. PRODUCTS FORMALLY ESCC, QML OR JAN QUALIFIED ARE DEEMED SUITABLE FOR USE IN AEROSPACE BY THE CORRESPONDING GOVERNMENTAL AGENCY.**

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2013 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

[www.st.com](http://www.st.com)